## **Electronic supplementary Information**

## Correlation between Platinum nanoparticle surface rearrangement induced by heat treatment and activity for an oxygen reduction reaction †

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ESI1. PES results of each sample.



Fig S1. PES measurements of Pt 4f spectra and fitting results for characterizing the Pt chemical state

## ESI2. ORR curves



**Fig S2.** Electrochemical RDE characterization (a) polarization curves for the ORR at 1600 rpm, (b) enlarged curves for comparing half wave potential and (c) specific activity at 1600 rpm and different potential (Tafel Plot)





Fig S3.  $CO_{ad}$  oxidation curve fitting results (a) REF, (b) H<sub>2</sub>, (c) Air, and (d) Ar



ESI4. Pre-peak of  $CO_{ad}$  oxidation results to confirm the change of defect site.

Fig S4. Pre-peak of  $CO_{ad}$  oxidation curve

ESI5. XANES whiteline absorption intensity and calculation

We compare the whiteline intensity as a calculation based on the theoretical curve. Lorentzian accounts transition to ground state superimposed on ac arc tangent function which is transition to continuum states. Integrated area of Lorentzian means the Pt d-band vacancy. The method to fitting the arc tangent and Lorentzian was referred to the previous papers. <sup>1, 2</sup>

The whiteline intensity was calculated the integral of fitted Lorentz and as shown in Figure S6.





Fig S6. XANES whiteline absorption intensity

- 1. R. Sousa Jr, F. Colmati, E. G. Ciapina and E. R. Gonzalez, *J. Solid State Electrochem.*, 2007, **11**, 1549-1557.
- 2. A. K. Shukla, R. K. Raman, N. A. Choudhury, K. R. Priolkar, P. R. Sarode, S. Emura and R. Kumashiro, *J. Electroanal. Chem.*, 2004, **563**, 181-190.